PowerMOS transistor Logic level FET

BUK555-100A/B

GENERAL DESCRIPTION

N-channel enhancement mode logic level field-effect power transistor in a plastic envelope. The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in automotive and general purpose switching applications.

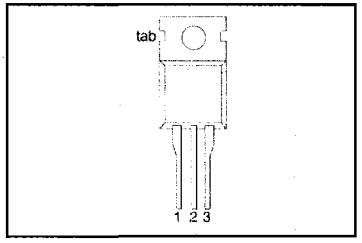
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
	BUK555	-100A	-100B	
V_{DS}	Drain-source voltage	100	100	V
I_D	Drain current (DC)	25	22	A
P_{tot}	Total power dissipation	125	125	W
T_j	Junction temperature	175	175	°C
$R_{DS(ON)}$	Drain-source on-state resistance; $V_{GS} = 5$ V	0.085	0.11	Ω

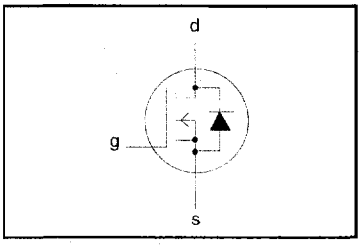
PINNING - TO220AB

PIN	DESCRIPTION
1	gate
2	drain
3	source
tab	drain

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT
V_{DS}	Drain-source voltage	-	-	100		V
V_{DGR}	Drain-gate voltage	$R_{GS} = 20$ kΩ	-	100		V
$\pm V_{GS}$	Gate-source voltage	-	-	15		V
$\pm V_{GSM}$	Non-repetitive gate-source voltage	$t_p \leq 50$ µs	-	20		V
				-100A	-100B	
I_D	Drain current (DC)	$T_{mb} = 25$ °C	-	25	22	A
I_D	Drain current (DC)	$T_{mb} = 100$ °C	-	18	15	A
I_{DM}	Drain current (pulse peak value)	$T_{mb} = 25$ °C	-	100	88	A
P_{tot}	Total power dissipation	$T_{mb} = 25$ °C	-	125		W
T_{stg}	Storage temperature	-	- 55	175		°C
T_j	Junction Temperature	-	-	175		°C

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ j\text{-}mb}$	Thermal resistance junction to mounting base		-	-	1.2	K/W
$R_{th\ j\text{-}a}$	Thermal resistance junction to ambient		-	60	-	K/W

STATIC CHARACTERISTICS

T_{mb} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V; I_D = 0.25 mA	100	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	V_{DS} = V_{GS}; I_D = 1 mA	1.0	1.5	2.0	V
I_{DSS}	Zero gate voltage drain current	V_{DS} = 100 V; V_{GS} = 0 V; T_j = 25 °C	-	1	10	µA
I_{DSS}	Zero gate voltage drain current	V_{DS} = 100 V; V_{GS} = 0 V; T_j =125 °C	-	0.1	1.0	mA
I_{GSS}	Gate source leakage current	V_{GS} = ±10 V; V_{DS} = 0 V	-	10	100	nA
$R_{DS(ON)}$	Drain-source on-state resistance	V_{GS} = 5 V; **BUK555-100A**	-	0.075	0.085	Ω
		I_D = 13 A **BUK555-100B**	-	0.09	0.11	Ω

DYNAMIC CHARACTERISTICS

T_{mb} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{fs}	Forward transconductance	V_{DS} = 25 V; I_D = 13 A	10	13.5	-	S
C_{iss}	Input capacitance	V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz	-	1450	1750	pF
C_{oss}	Output capacitance		-	280	350	pF
C_{rss}	Feedback capacitance		-	100	150	pF
$t_{d\,on}$	Turn-on delay time	V_{DD} = 30 V; I_D = 3 A;	-	25	40	ns
t_r	Turn-on rise time	V_{GS} = 5 V; R_{GS} = 50 Ω;	-	65	85	ns
$t_{d\,off}$	Turn-off delay time	R_{gen} = 50 Ω	-	135	180	ns
t_f	Turn-off fall time		-	80	110	ns
L_d	Internal drain inductance	Measured from contact screw on tab to centre of die	-	3.5	-	nH
L_d	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
L_s	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nH

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

T_{mb} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	25	A
I_{DRM}	Pulsed reverse drain current	-	-	-	100	A
V_{SD}	Diode forward voltage	I_F = 25 A ; V_{GS} = 0 V	-	1.3	1.7	V
t_{rr}	Reverse recovery time	I_F = 25 A; -dI_F/dt = 100 A/µs;	-	90	-	ns
Q_{rr}	Reverse recovery charge	V_{GS} = 0 V; V_R = 30 V	-	0.8	-	µC

AVALANCHE LIMITING VALUE

T_{mb} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
W_{DSS}	Drain-source non-repetitive unclamped inductive turn-off energy	I_D = 25 A ; V_{DD} ≤ 50 V ; V_{GS} = 5 V ; R_{GS} = 50 Ω	-	-	140	mJ

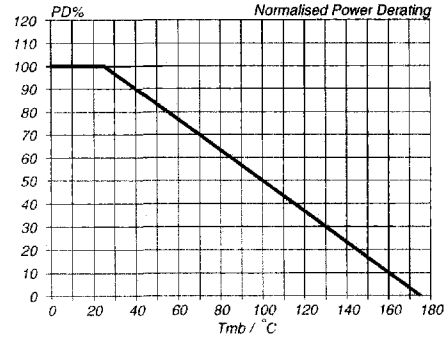


Fig.1. Normalised power dissipation.
PD% = 100·P_D/$P_{D\ 25\ °C}$ = f(T_{mb})

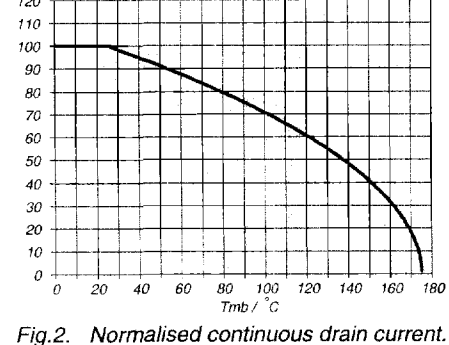


Fig.2. Normalised continuous drain current.
ID% = 100·I_D/$I_{D\ 25\ °C}$ = f(T_{mb}); conditions: V_{GS} ≥ 5 V

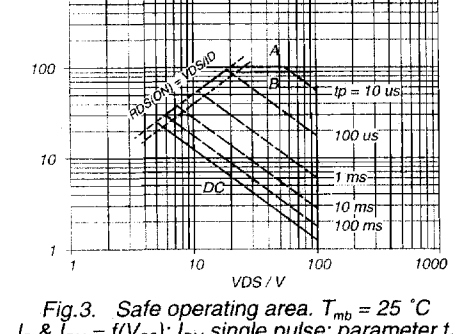


Fig.3. Safe operating area. T_{mb} = 25 °C
I_D & I_{DM} = f(V_{DS}); I_{DM} single pulse; parameter t_p

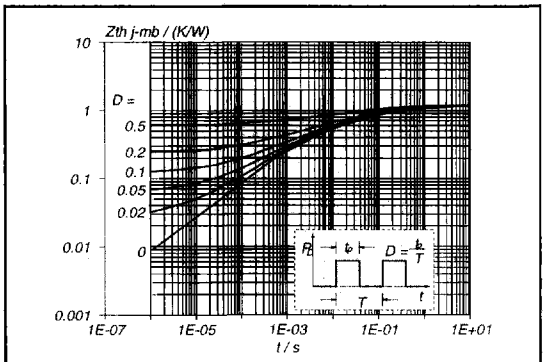


Fig.4. Transient thermal impedance.
$Z_{th\ j\text{-}mb}$ = f(t); parameter D = t_p/T

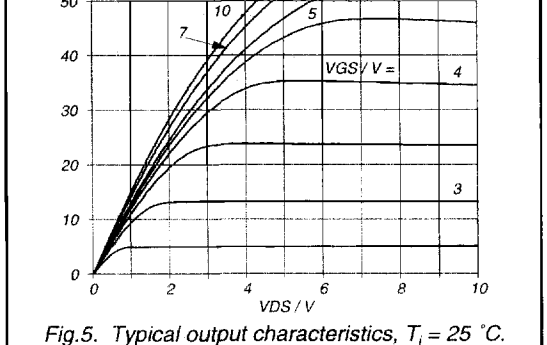


Fig.5. Typical output characteristics, T_j = 25 °C.
I_D = f(V_{DS}); parameter V_{GS}

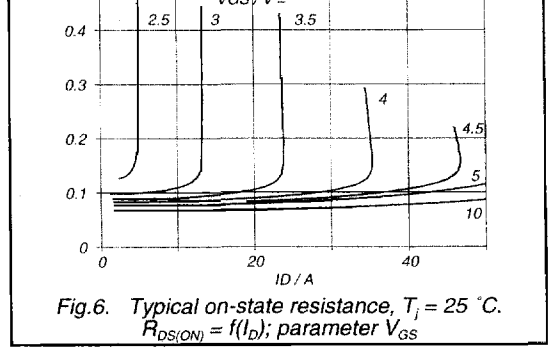


Fig.6. Typical on-state resistance, T_j = 25 °C.
$R_{DS(ON)}$ = f(I_D); parameter V_{GS}

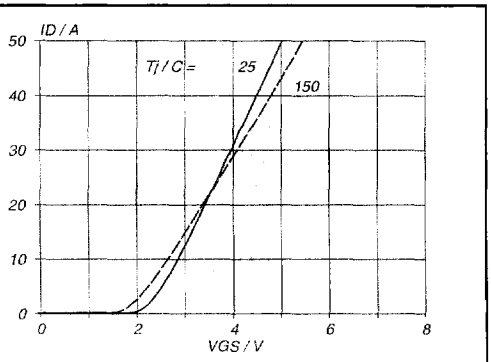


Fig.7. Typical transfer characteristics.
$I_D = f(V_{GS})$; conditions: V_{DS} = 25 V; parameter T_j

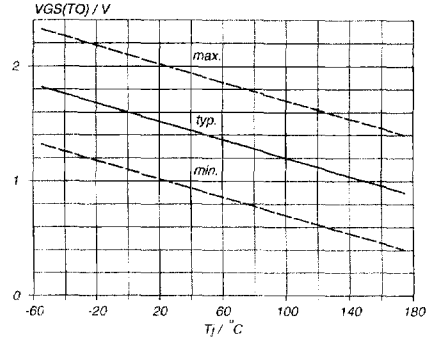


Fig.10. Gate threshold voltage.
$V_{GS(TO)} = f(T_j)$; conditions: I_D = 1 mA; $V_{DS} = V_{GS}$

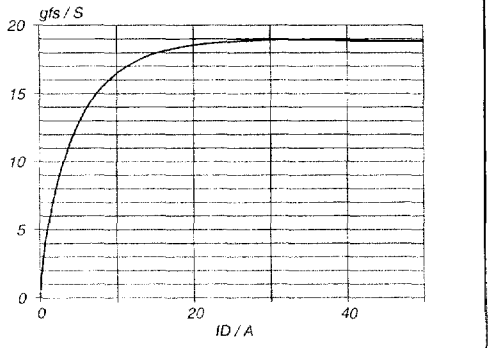


Fig.8. Typical transconductance, T_j = 25 °C.
$g_{fs} = f(I_D)$; conditions: V_{DS} = 25 V

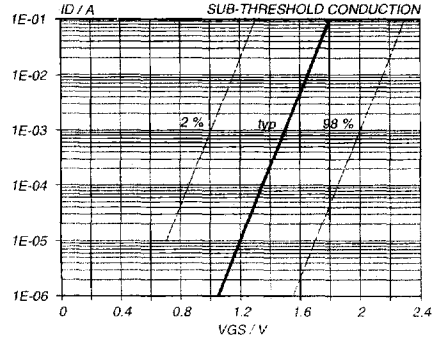


Fig.11. Sub-threshold drain current.
$I_D = f(V_{GS})$; conditions: T_j = 25 °C; $V_{DS} = V_{GS}$

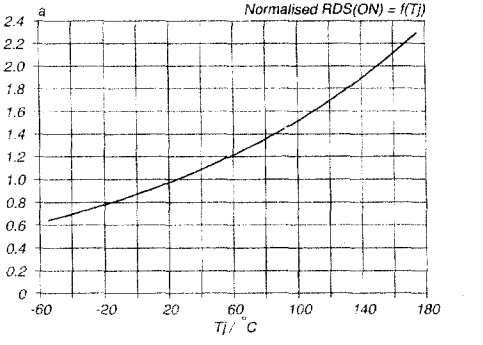


Fig.9. Normalised drain-source on-state resistance.
$a = R_{DS(ON)}/R_{DS(ON)25\,°C} = f(T_j)$; I_D = 13 A; V_{GS} = 5 V

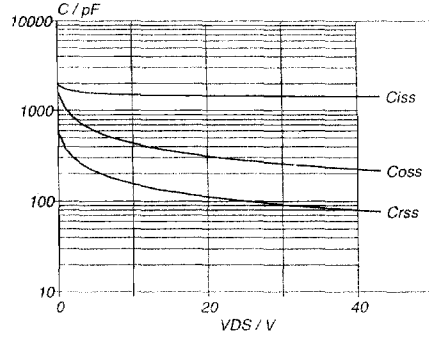


Fig.12. Typical capacitances, C_{iss}, C_{oss}, C_{rss}.
$C = f(V_{DS})$; conditions: V_{GS} = 0 V; f = 1 MHz

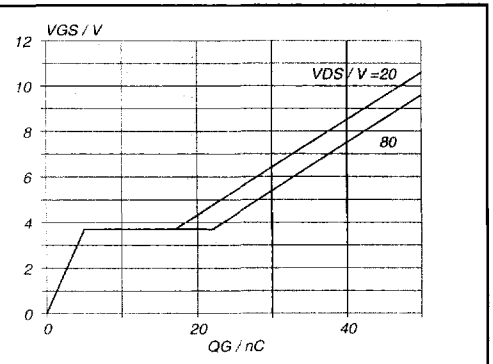


Fig.13. Typical turn-on gate-charge characteristics. $V_{GS} = f(Q_G)$; conditions: $I_D = 25$ A; parameter V_{DS}

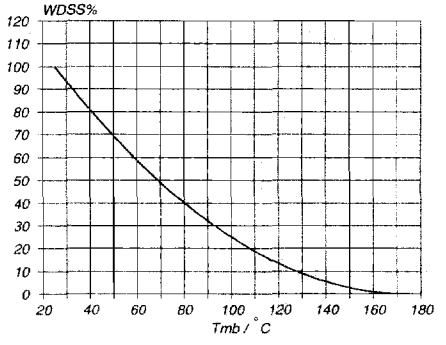


Fig.15. Normalised avalanche energy rating. $W_{DSS}\% = f(T_{mb})$; conditions: $I_D = 25$ A

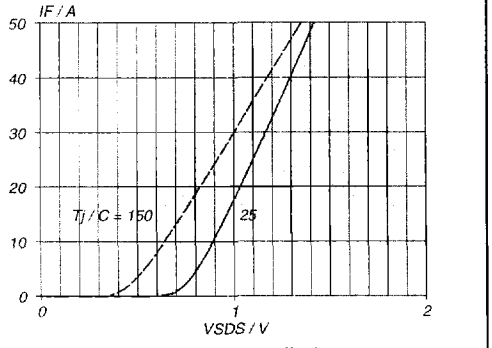


Fig.14. Typical reverse diode current. $I_F = f(V_{SDS})$; conditions: $V_{GS} = 0$ V; parameter T_j

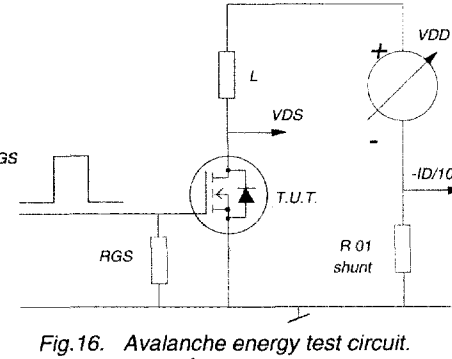


Fig.16. Avalanche energy test circuit.
$$W_{DSS} = 0.5 \cdot LI_D^2 \cdot BV_{DSS}/(BV_{DSS} - V_{DD})$$